minium sample holder similar to the platinum holder used for high temperatures. The sample is fixed to a 0·01–0·02 mm thick nickel foil (Cu $K\beta$ filter thickness) using epoxy glue. The nickel foil gives a good thermal contact with the bulk sample holder, and also serves as an attenuator for fluorescent radiation. Normally, we employ Cu $K\alpha$ radiation as it is not attenuated significantly by the beryllium windows which are mounted on the chamber to facilitate the transmission of X-rays under vacuum conditions ($\sim 5 \times 10^{-8}$ Pa).

Temperatures are measured by means of calibrated Pt and Ge resistance thermometers and a calibrated bridge. The temperature at any given time is estimated by comparing cooling and heating curves as measured by the thermometers with the traverse of the film. The diffraction pattern has a width of 5 mm on the film. We have found agreement between sample temperature and the reading of the thermometers by observing the phase transitions of KH_2PO_4 (123 K) and $TbVO_4$ (32 K). The fastest cool-down time to lowest temperature is ~75 min and when using a film speed of 15 mm h^{-1}, the precision of our temperature indication as estimated from line splitting of phase transitions is about ± 10 K. The line splittings observed for the two test substances are very clear due to the good resolving power of the Guinier method.

The main purpose of this present equipment is to obtain a quick indication of low-temperature phase transitions. Detailed single-crystal investigations can then be carried out using a four-circle diffractometer attachment described separately (Henriksen, Larsen & Rasmussen, 1986).

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Crystallographers

J. Appl. Cryst. (1986). **19**, 414

This section is intended to be a series of short paragraphs dealing with the activities of crystallographers, such as their changes of position, promotions, assumption of significant new duties, honours, etc. Items for inclusion, subject to the approval of the Editorial Board, should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England).

Wallace Conrad Koehler died of cancer on 1 April 1986 at the age of 65. He was a distinguished scientist in the Solid State Division of the Oak Ridge National Laboratory and served as Director of the ORNL National Center for Small Angle Scattering Research (NCSASR). He received the BS and MS degrees from the University of Chicago in 1943 and 1948 respectively, and the PhD degree from the University of Tennessee in 1953. He was awarded the degree of Docteur Honoris Causa in 1979 by the University of Grenoble. Dr M. K. Wilkinson and Dr R. M. Moon write that Koehler was a pioneer in the development and use of neutron scattering techniques; he joined the program of C. G. Shull and E. O. Wollan at ORNL in its very early stage. This pioneering work has helped to lay the foundation on which neutron scattering programs throughout the world have been built. Koehler was particularly interested in studying the magnetic properties of rare-earth materials, and he became a leading authority on this subject. In 1983 he was co-recipient (with S. Legvold of Ames Laboratory and Iowa State University) of the Frank H. Spedding rare-earth award. His recent research involved small-angle scattering techniques and, under his direction, NCSASR became a very successful user program that accommodated over 100 scientists annually. Wally Koehler was an exceptionally kind person who liked people; he quickly became a good friend of everyone who knew him. His excellent research investigations brought him into contact with scientists throughout the world, and he will be greatly missed by a large segment of the scientific community.

Brian W. Matthews of the University of Oregon has been elected to the National Academy of Sciences in recognition of his achievements in molecular biology research.

Bi-Cheng Wang, formerly with the Biocrystallography Laboratory of the VA Medical Center in Pittsburgh, has been appointed Professor of Crystallography and Biological Sciences at the University of Pittsburgh.

Professor **M. M. Woolfson**, Professor and Head of the Department of Physics at the University of York, has been awarded the Hughes medal of the Royal Society, as the creator of algorithms such as *MULTAN* and *SAYTAN*, which are used worldwide to solve the majority of reported crystal structures.

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